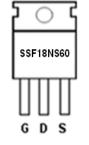
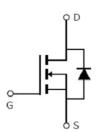


### **Main Product Characteristics:**

V <sub>DSS</sub>	610V
R <sub>DS</sub> (on)	0.27Ω(typ.)
I <sub>D</sub>	15A ①







TO220

Marking and pin
Assignment

Schematic diagram

### **Features and Benefits:**

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance



### **Description:**

The SSF18NS60 series MOSFETs is a new technology. which combines an innovative super junction technology and advance process. This new technology achieves low Rdson, energy saving, high reliability and uniformity, superior power density and space saving.

# **Absolute max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	15 ①	
I <sub>D</sub> @ TC = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	9.4 ①	Α
I <sub>DM</sub>	Pulsed Drain Current ②	60	
D @TC 25°C	Power Dissipation ③	156	W
P <sub>D</sub> @TC = 25°C	Linear Derating Factor	1.25	W/°C
V <sub>DS</sub>	Drain-Source Voltage	610	V
V <sub>GS</sub>	Gate-to-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy @ L=22.5mH		mJ
I <sub>AS</sub>	Avalanche Current @ L=22.5mH	4	Α
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to + 150	°C



### **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
R <sub>0</sub> JC	Junction-to-case ③	_	0.8	°C/W
$R_{\theta JA}$	Junction-to-ambient (t $\leq$ 10s) (4)	_	62	°C/W

# **Electrical Characterizes** $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	610	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
D	0 0		0.27	0.35		$V_{GS}=10V, I_{D}=9.4A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	0.73	_	Ω	T <sub>J</sub> = 125℃
V	Cata threshold voltage	2	_	4	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
$V_{GS(th)}$	Gate threshold voltage	_	2.66	_	V	T <sub>J</sub> = 125℃
1	Drain to Source leakage current	_	_	1	^	$V_{DS} = 600V, V_{GS} = 0V$
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	50	μA	T <sub>J</sub> = 125°C
Lana	Gate-to-Source forward leakage	_	_	100	nA	V <sub>GS</sub> =30V
I <sub>GSS</sub> Gate	sate-to-Source forward leakage	_	_	-100	IIA	V <sub>GS</sub> = -30V
$Q_g$	Total gate charge	_	27.0	_		$I_D = 10A,$
$Q_{gs}$	Gate-to-Source charge	_	6.3	_	nC	V <sub>DS</sub> =480V,
$Q_{gd}$	Gate-to-Drain("Miller") charge	_	13.7	_		V <sub>GS</sub> = 10V
t <sub>d(on)</sub>	Turn-on delay time	_	12.3	_		V <sub>GS</sub> =10V, V <sub>DS</sub> =480V,
t <sub>r</sub>	Rise time	_	24.3	_	nS	$R_L=40\Omega$ ,
t <sub>d(off)</sub>	Turn-Off delay time	_	27.1	_	113	R <sub>GEN</sub> =4.1Ω
tf	Fall time	_	19.7	_		I <sub>D</sub> =12A
C <sub>iss</sub>	Input capacitance	_	949	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	783	_	pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse transfer capacitance	_	11	_		f = 400KHz

# **Source-Drain Ratings and Characteristics**

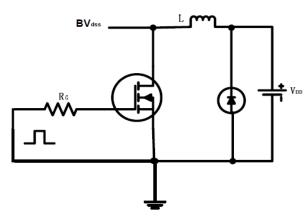
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current		_	15 ①	А	MOSFET symbol
Is	(Body Diode)	_				showing the
I <sub>SM</sub>	Pulsed Source Current		_	60	А	integral reverse
	(Body Diode)	_				p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	0.89	1.3	V	I <sub>S</sub> =15A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	_	313	_	nS	$T_J = 25^{\circ}C$ , $I_F = 15A$ , $di/dt =$
Q <sub>rr</sub>	Reverse Recovery Charge	_	3	_	μC	100A/μs

Version: 1.1

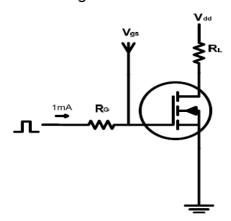


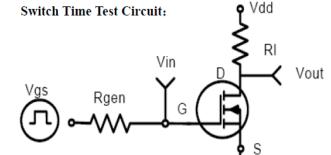
### **Test circuits and Waveforms**

#### **EAS** test circuits:

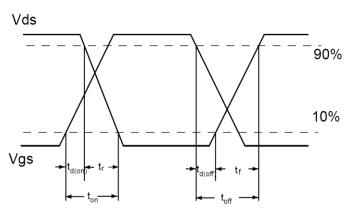


#### Gate charge test circuit:





#### **Switch Waveforms:**



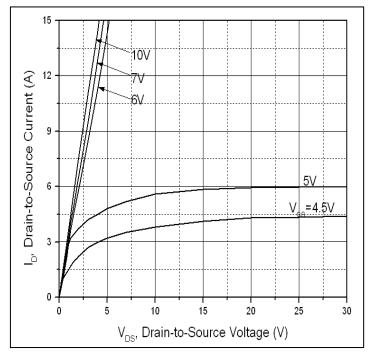
#### Notes:

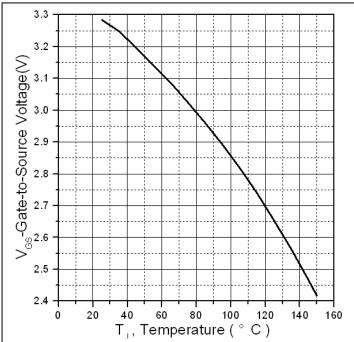
- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of  $R_{\texttt{9JA}}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- ⑤These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}=150$ °C.

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# Typical electrical and thermal characteristics





**Figure 1: Typical Output Characteristics** 

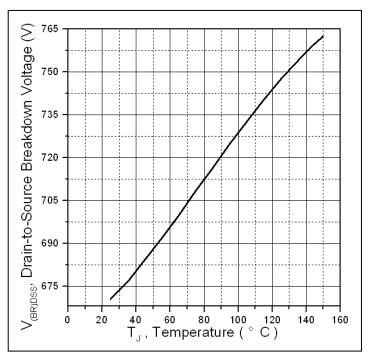


Figure 3. Drain-to-Source Breakdown Voltage vs.
Temperature

Figure 2. Gate to source cut-off voltage

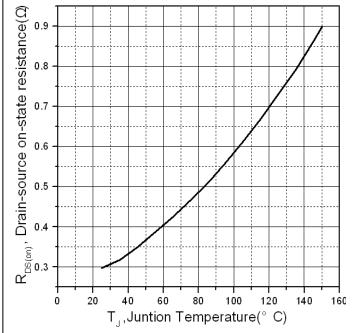
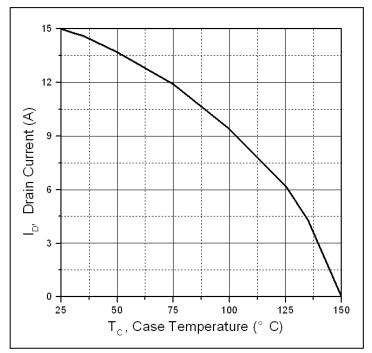


Figure 4: Normalized On-Resistance Vs. Case Temperature



# Typical electrical and thermal characteristics



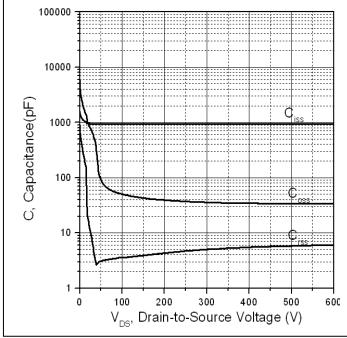
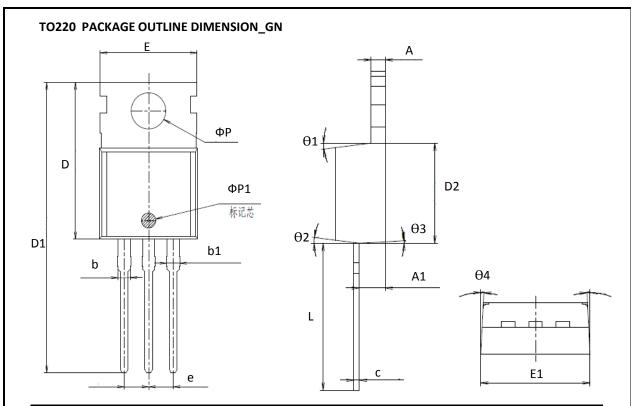


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage



# **Mechanical Data:**



Symbol	Dime	nsion In Millin	neters	Dimension In Inches		
Syllibol	Min	Nom	Max	Min	Nom	Max
Α	-	1.300	-	-	0.051	-
A1	2.200	2.400	2.600	0.087	0.094	0.102
b	-	1.270	-	-	0.050	-
b1	1.270	1.370	1.470	0.050	0.054	0.058
С	-	0.500	-	-	0.020	-
D	-	15.600	-	-	0.614	-
D1	-	28.700	-	-	1.130	-
D2	-	9.150	-	-	0.360	-
Е	9.900	10.000	10.100	0.390	0.394	0.398
E1	-	10.160	-	-	0.400	-
ΦР	-	3.600	-	-	0.142	-
ФР1		1.500			0.059	
е		2.54BSC			0.1BSC	
L	12.900	13.100	13.300	0.508	0.516	0.524
Θ1	-	<b>7</b> <sup>0</sup>	-	-	7 <sup>0</sup>	-
Θ2	-	<b>7</b> <sup>0</sup>	-	-	7 <sup>0</sup>	-
Θ3	-	30	-	5 <sup>0</sup>	7 <sup>0</sup>	90
Θ4	-	<b>3</b> <sup>0</sup>	-	1 <sup>0</sup>	3 <sup>0</sup>	5 <sup>0</sup>





# **Ordering and Marking Information**

Device Marking: SSF18NS60

Package (Available)
TO220
Operating Temperature Range
C: -55 to 150 °C

# **Devices per Unit**

Package	Units/	Tubes/Inner		InnerBoxes/	Units/Carton
Type	Tube	Box		CartonBox	Box
TO220	50	20	1000	6	6000

**Reliability Test Program** 

Test Item	Conditions	Duration	Sample Size
High	T <sub>j</sub> =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V <sub>DSS</sub> /V <sub>CES</sub> /VR	1000 hours	
Bias(HTRB)			
High	T <sub>j</sub> =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V <sub>GSS</sub>	500 hours	
Gate		1000 hours	
Bias(HTGB)			

Version: 1.1



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